

User Guide

MCU LSE Crystal Selection Guide

Introduction

This document details the LSE crystal selection guide to provide users with a reference.

This document is only applicable to Nsing MCU products. Currently, the supported product series include N32G43X series, N32L40X series, N32L43X series.

Contents

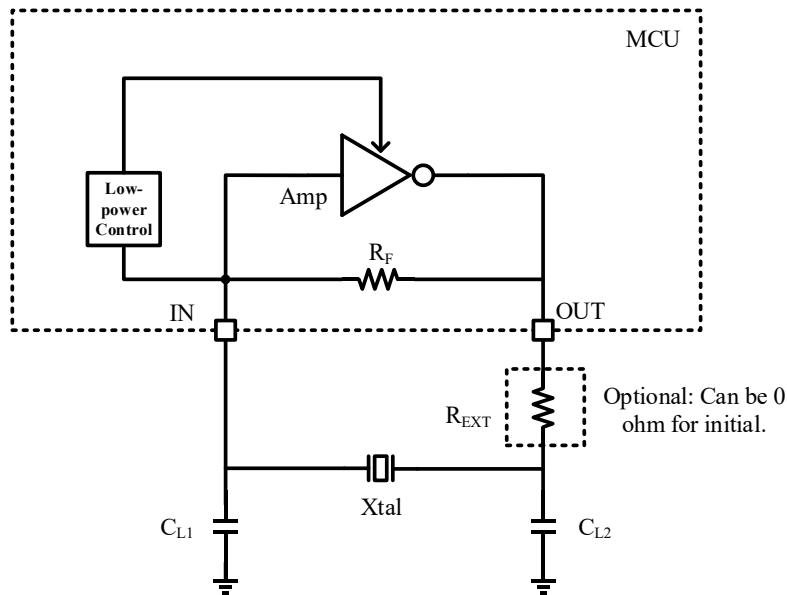
1.	LSE Crystal Selection Instructions.....	3
1.1	External Crystal Circuit	3
1.2	LSE Matching Capacitance Calculation	3
1.3	LSE Crystal Test	4
1.3.1	LSE Crystal Parameter Configuration	4
1.3.2	Crystal Frequency Test.....	5
1.3.3	Power Consumption Test	7
1.3.4	Crystal Compatibility List.....	8
2.	Version History.....	10
3.	Disclaimer	11

1. LSE Crystal Selection Instructions

1.1 External Crystal Circuit

Figure 1-1 shows the typical design of LSE external crystal, where R_F feedback resistor has been designed inside the chip, so users do not need to add this resistor outside the chip.

Figure 1-1 A Typical Application Using 32.768KHz Crystals



1.2 LSE Matching Capacitance Calculation

The low-speed external clock (LSE) can be generated using an oscillator consisting of a 32.768kHz crystal/ceramic resonator. In applications, crystal and load capacitors must be as close to the oscillator pins as possible to minimize output distortion and stabilization time at startup. For detailed crystal parameters (frequency, package, accuracy, etc.), please consult the appropriate manufacturer.

For C_{L1} and C_{L2} , it is recommended to use ceramic capacitors to match the requirements of the crystal. Usually, C_{L1} and C_{L2} have the same capacitance value.

Load capacitance C_L is calculated by the following formula:

$$C_L = \frac{C_{L1} \times C_{L2}}{C_{L1} + C_{L2}} + C_{stray}$$

C_{stray} is stray capacitance, sum of the device pin and the PCB (a parasitic) capacitances.

For example, if a load capacitor is selected $C_L = 7\text{pF}$ crystal, and $C_{stray} = 1\text{pF}$,

$$C_L - C_{stray} = \frac{C_{L1} \times C_{L2}}{C_{L1} + C_{L2}} = 6 \text{ pF}$$

hence $C_{L1} = C_{L2} = 12 \text{ pF}$.

1.3 LSE Crystal Test

1.3.1 LSE Crystal Parameter Configuration

When LSE external crystal is used, void RCC_ConfigLse(uint8_t RCC_LSE, uint16_t LSE_Trim) function is called and parameter uint16_t LSE_Trim is used to configure crystal parameters, as shown in the following code example:

Figure 1-1 RCC_Config LSE Function

```

/**
 * @brief Configures the External Low Speed oscillator (LSE).
 * @param RCC_LSE specifies the new state of the LSE.
 * This parameter can be one of the following values:
 * @arg RCC_LSE_DISABLE LSE oscillator OFF
 * @arg RCC_LSE_ENABLE LSE oscillator ON
 * @arg RCC_LSE_BYPASS LSE oscillator bypassed with external clock
 * @param LSE_Trim specifies LSE Driver Trim Level.
 */
void RCC_ConfigLse(uint8_t RCC_LSE, uint16_t LSE_Trim)
{
    //PWR DBP set 1
    /* Enable PWR Clock */
    RCC_EnableAPB1PeriphClk(RCC_APB1_PERIPH_PWR, ENABLE);
    PWR->CTRL1 |= 0x100;
    /* Check the parameters */
    assert_param(IS_RCC_LSE(RCC_LSE));
    /* Reset LSEEN LSEBYP and LSECLKSSEN bits before configuring the LSE -----*/
    *(__IO uint32_t*)LDCTRL_ADDR &= ~(RCC_LDCTRL_LSEEN | RCC_LDCTRL_LSEBP | RCC_LDCTRL_LSECLKSSEN);
    /* Configure LSE (RCC_LSE_DISABLE is already covered by the code section above) */
    switch (RCC_LSE)
    {
    case RCC_LSE_ENABLE:
        /* Set LSEON bit */
        *(__IO uint32_t*)LDCTRL_ADDR |= RCC_LSE_ENABLE;
        LSE_XtalConfig(LSE_Trim);
        break;
    case RCC_LSE_BYPASS:
        /* Set LSEBYP and LSEON bits */
        *(__IO uint32_t*)LDCTRL_ADDR |= (RCC_LSE_BYPASS | RCC_LSE_ENABLE);
        break;
    default:
        break;
    }
}

```

Table 1-1 lists two recommended configuration values. Different configuration values have a great influence on the final crystal properties, as follows:

- 1) **Low power configuration (configuration values: 0xFF)** : compared with the default configuration after the chip is powered on, this configuration enhances the LSE driver capability and supports more crystal models.
- 2) **Normal configuration (configuration values: 0x1FF)** : At the same time, both the driving capability and steady-state operating current of the LSE are enhanced, and the crystal compatibility is further improved. This configuration value is relatively low-power configuration, and the power consumption of the crystal circuit is slightly increased.

Table 1-1 Comparison of LSE Configuration Values

Configuration Items	Configuration Values
Low power configuration	0xFF

Normal configuration	0x1FF
----------------------	-------

The following sections will provide the test data of different crystal parameter configuration values for customer application.

1.3.2 Crystal Frequency Test

1.3.2.1 Normal Temperature Frequency Test

In LSE design, it is necessary to select the appropriate matching capacitance and crystal configuration values. Refer to the peripheral hardware design in Figure 1-1, select a crystal and connect the capacitor to test the crystal frequency. The crystal signal can be output to the frequency meter or other frequency testing instruments through MCO.

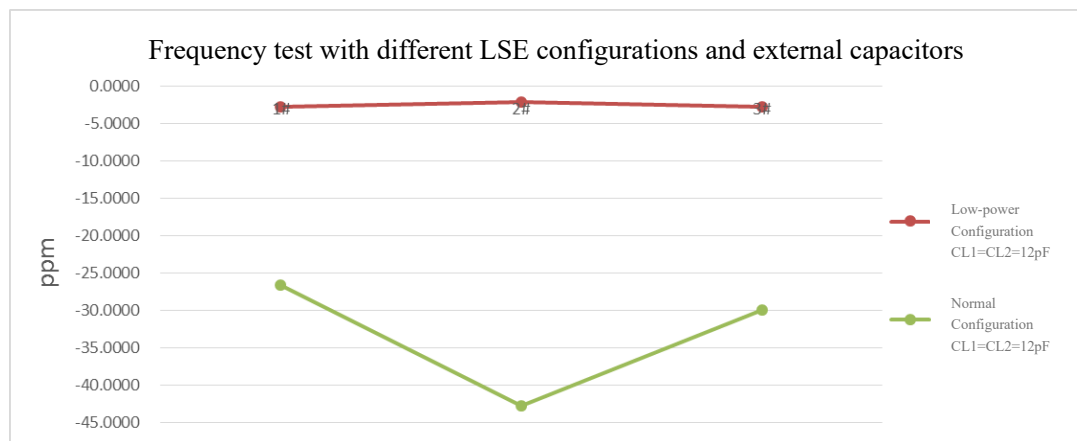
- Test example:

The selected crystal load capacitance $C_L = 7\text{pF}$, C_{stray} calculated at 1pF , then $C_{L1} = C_{L2} = 12\text{pF}$.

Note: C_{stray} is related to different test board hardware. Users can fine-tune the external capacitors C_{L1} and C_{L2} based on the test frequency.

As shown in Figure 1-2, C_{L1} and C_{L2} chip capacitance is 12pF , and the crystal output frequency of the three test plates is compared as follows.

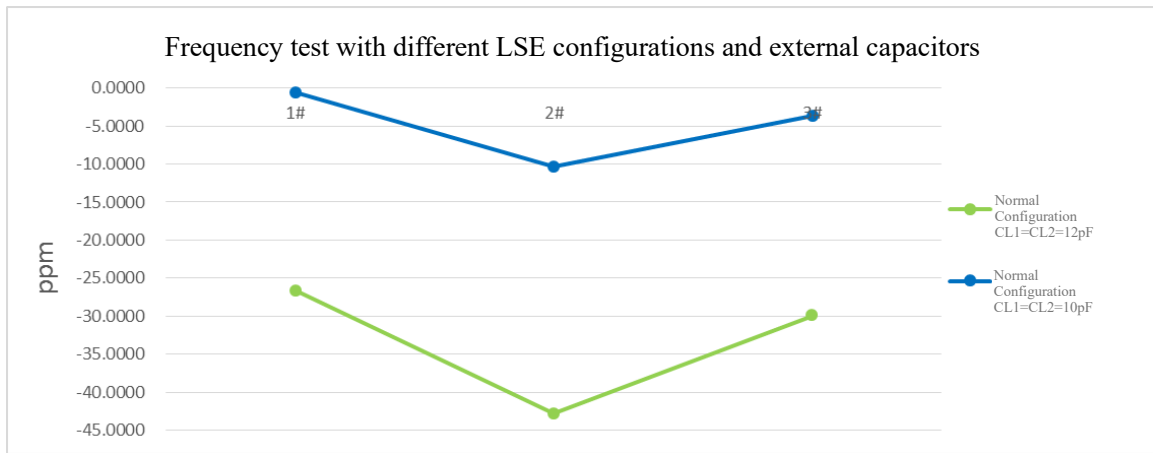
Figure 1-2 LSE Output Frequency (25°C, $C_{L1} = C_{L2} = 12\text{pF}$)



As shown in Figure 1-2, the same hardware design and different configuration values have certain influence on the frequency. In normal configuration, the frequency is lower than that in low-power configuration, and is less than -20ppm. In this case, the crystal frequency can be increased by decreasing C_{L1} and C_{L2} .

As shown in Figure 1-3, C_{L1} and C_{L2} patch capacitance is adjusted from 12pF to 10pF (for the normal configuration), and the output frequency of the three test boards is compared before and after the capacitor is adjusted.

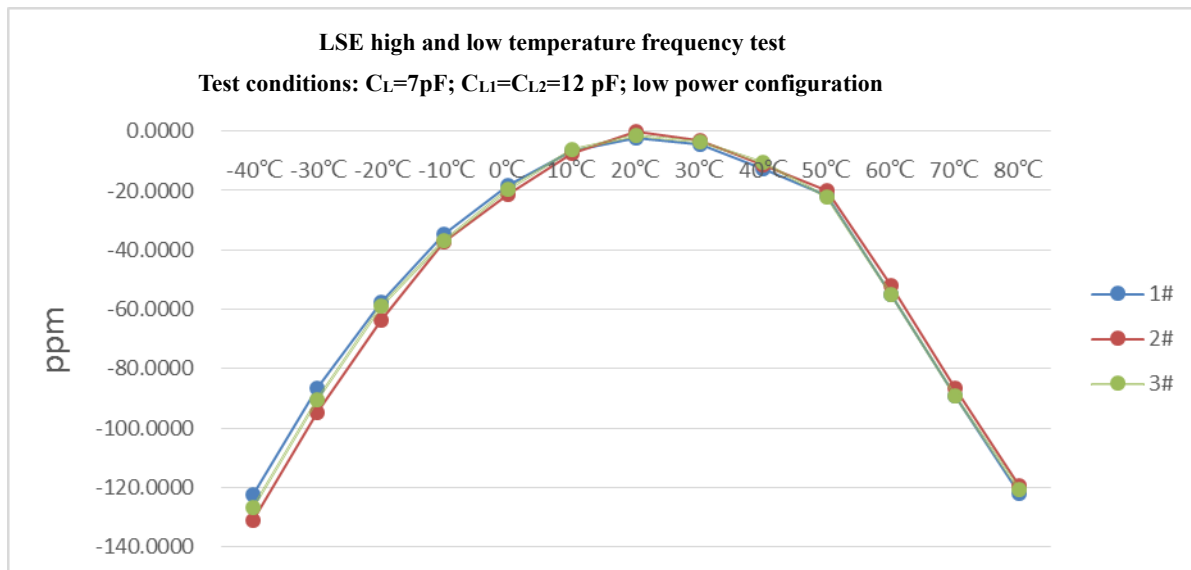
Figure 1-3 LSE Output Frequency (25°C, C_{L1} = C_{L2} = 12 or 10 pF)



1.3.2.2 High and Low Temperature Frequency Test

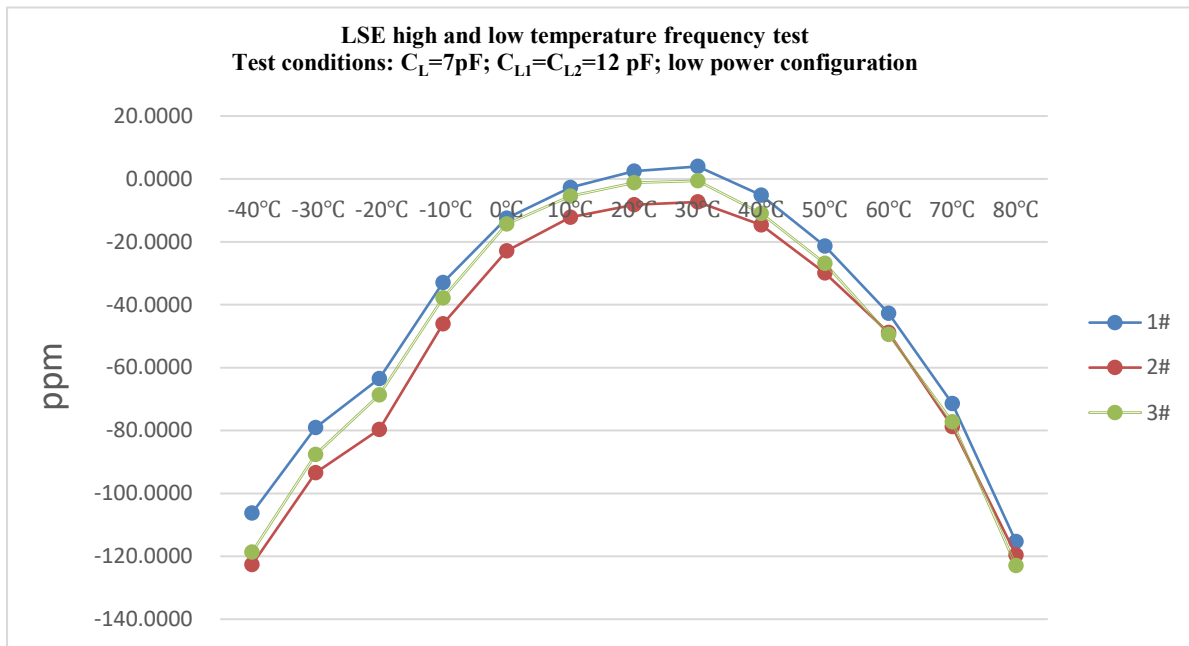
Refer to Figure 1-4 for the LSE output frequency in the low-power configuration at high and low temperatures.

Figure 1-4 Low Power Configuration Value, LSE High and Low Temperature Output Frequency



Refer to Figure 1-5 for the LSE output frequency in normal configuration at high and low temperature.

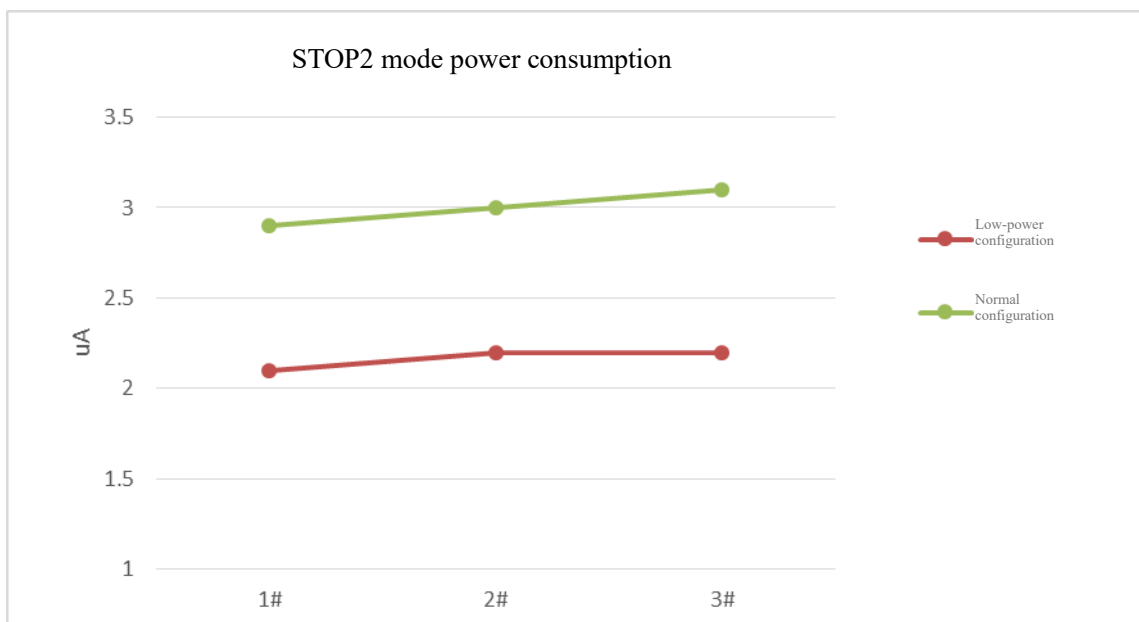
Figure 1-5 Normal Configuration Value, LSE High and Low Temperature Output Frequency



1.3.3 Power Consumption Test

Figure 1-6 shows the power consumption of the chip in different configurations. Compared with normal configuration, the power consumption in STOP2 mode increases about 0.8uA.

Figure 1-6 STOP2 Mode Power Consumption under Different Register Configuration Conditions



1.3.4 Crystal Compatibility List

When choosing a 32.768kHz external crystal for N32G43X/N32L40X/N32L43X series MCU, it is important to ensure that the selected crystal can operate within the full temperature range.

The crystal configuration parameters of the chip are different, and the adaptable crystal models are also different. Refer to Table 1-2 for the crystal compatibility list for full temperature test. The crystals in this list can be compatible with both low power configuration values and normal configuration values.

Table 1-2 LSE Crystal Compatibility List

No.	Crystal Model	Package	Manufacturer	CL (pF)	CO (pF)	ESR(max) (kΩ)	Temperature Range (°C)
1	TFX-04-32.768K(7PF)	1610	RIVER	7	1.3	90	-40~85
2	TFX-04-32.768K			12.5	1.3	90	
3	1TJH090DR1A0086		KDS	9	1.3	90	
4	DST1610A 32.768KHz			12.5	1.3	90	
5	X1A0001210005		EPSON	12.5	1.2	90	
6	SC-16S 32.768kHz 20PPM 12.5pF		SEIKO	12.5	1.2	90	
7	FC-12M 32.768000 kHz 7.0+20.0-20.0/X1A0000610006	2012	EPSON	7	1.3	90	
8	TJXM32768K2TGDCNT2T		TAE	12.5		70	
9	1TJG125DR1A0019		KDS	12.5	1.3	80	
10	FC-135R 32.768KHz 9PF 20PPM/X1A0001410002	3215	EPSON	9	1.1	50	
11	FC-135 32.768KHz 9PF 20PPM/Q13FC13500003			9	1	70	
12	FC-135 32.768KHz 12.5PF 20PPM/Q13FC13500004			12.5	1.2	70	
13	FC-135 32.768KHz 9PF 20PPM/FC-135 32.7680KA-AC			9	1	70	
14	SC-32S 32.768kHz 7pF 20ppm		SEIKO	7	1	70	
15	SC-32S 32.768kHz 12.5pF 20ppm			12.5	1	70	
16	SC-32S 32.768kHz 9pF 20ppm			9	1	70	
17	1TJF125DP1A000A		KDS	12.5	1.3	80	
18	7LC32768F12UC		SJK	12.5	1.2	70	
19	FC31M2-32.768-NTLLLDLT		HCI	12.5	1.5	70	
20	X321532768KGD2SI		YXC	12.5	1.2	70	
21	ETST00327000JE		HOSONIC	12.5	2	70	
22	TCXM32768K2NGDCZT2T		TAE	12.5	2	80	
23	XDMCZLNDDF-0.032768MHZ	TAITIEN	12.5				
24	KFC3276812520	KYX	12.5	1.2	70		
25	F3K232768PWQAC	JYJE	12.5		70		
26	26S-32.768-12.5-10-10/B	DT26	LIMING	12.5		90	

27	MC-146 32.768KHz 9PF 20PPM/ Q13MC14610004	MC-146	EPSON	9	0.8	65	
28	MC-146 32.768KHz 12.5PF 20PPM/ Q13MC14620002			12.5	0.8	65	
29	SSP-T7-F 32.768kHz 20PPM 7pF		SEIKO	7	0.8	65	
30	FR07S4-32.768-N07LLDT		HCI	7	0.8	65	
31	FR07S4-32.768-NTLLLDLT			12.5	0.8	65	
32	TSXM32768K4KGDCZT3T		TAE	12.5	0.8	65	
33	7MC32768F12UC		SJK	12.5	1.2	70	
34	M132768PWPAC		JYJE	12.5		65	
35	CD01K032768FEPBAEAE	DT26	TKD	8	1.4	40	-20~70
36	CD01K032768ACNBAEAE			12.5	1.4	40	
37	CD01K032768DGRBAEAE			6	1.4	40	
38	Y26003271C2040DYJY		JGHC	12.5		40	
39	X206032768KGB2SC		YXC	12.5		40	
40	146-32.768-12.5-20-20/A	MC-146	LIMING	12.5			
41	7L032768NW2		HD	12.5	0.8	65	
42	X308032768KGB2SC	DT38	YXC	12.5		40	
43	CD02K032768AEPBAEAE		TKD	12.5	1.8	30	
44	WTL3T45322LZ		WTL	12.5	1.5	40	
45	SMD31327681252090	3215	JGHC	12.5	1	65	-10~60
46	S3132768072070			7	1	65	
47	DT-38 32.768KHz	DT38	KDS	12.5	1.3	30	
48	Y308327681252075		JGHC	12.5	1.1	40	

Note: Above crystal compatibility test of the chip supply voltage $V_{DD} = 3.3 V$.

2. Version History

Version	Date	Changes
V1.0	2022.04.27	Initial version

3. Disclaimer

This document is the exclusive property of NSING TECHNOLOGIES PTE. LTD.(Hereinafter referred to as NSING).

This document, and the product of NSING described herein (Hereinafter referred to as the Product) are owned by NSING under the laws and treaties of Republic of Singapore and other applicable jurisdictions worldwide. The intellectual properties of the product belong to Nations Technologies Inc. and Nations Technologies Inc. does not grant any third party any license under its patents, copyrights, trademarks, or other intellectual property rights. Names and brands of third party may be mentioned or referred thereto (if any) for identification purposes only. NSING reserves the right to make changes, corrections, enhancements, modifications, and improvements to this document at any time without notice. Please contact NSING and obtain the latest version of this document before placing orders.

Although NATIONS has attempted to provide accurate and reliable information, NATIONS assumes no responsibility for the accuracy and reliability of this document. It is the responsibility of the user of this document to properly design, program, and test the functionality and safety of any application made of this information and any resulting product. In no event shall NATIONS be liable for any direct, indirect, incidental, special, exemplary, or consequential damages arising in any way out of the use of this document or the Product.

NATIONS Products are neither intended nor warranted for usage in systems or equipment, any malfunction or failure of which may cause loss of human life, bodily injury or severe property damage. Such applications are deemed, Insecure Usage'. Insecure usage includes, but is not limited to: equipment for surgical implementation, atomic energy control instruments, airplane or spaceship instruments, all types of safety devices, and other applications intended to supporter sustain life. All Insecure Usage shall be made at user's risk. User shall indemnify NATIONS and hold NATIONS harmless from and against all claims, costs, damages, and other liabilities, arising from or related to any customer's Insecure Usage Any express or implied warranty with regard to this document or the Product, including, but not limited to. The warranties of merchantability, fitness for a particular purpose and non-infringement are disclaimed to the fullest extent permitted by law. Unless otherwise explicitly permitted by NATIONS, anyone may not use, duplicate, modify, transcribe or otherwise distribute this document for any purposes, in whole or in part.